半導體設備資安測試項目代碼為 1604E013(半導體設備之資安測試)

認證項目內容：

試驗件	試驗項目	試驗方法	試驗範圍
半導體設備	資通安全性測試	● SEMI E187 - Specification for Cybersecurity of Fab Equipment V1.0 ● 以 SEMI E187 為基礎之半導體設備資安查核規範 V1.0	含遊測 僅遊測
Semiconductor Equipment	Information security Test	● SEMI E187 - Specification for Cybersecurity of Fab Equipment V1.0 ● Semiconductor Equipment cybersecurity Validation Criteria based on SEMI E187 V1.0	on-site testing included on-site testing